PATENT
8020-1036

**IN THE U.S. PATENT AND TRADEMARK OFFICE**

In re application of
SAITO et al.

Application No. 10/774,463

Filed February 10, 2004

EVALUATION WIRING PATTERN AND EVALUATION METHOD FOR EVALUATING RELIABILITY OF SEMICONDUCTOR DEVICE, AND SEMICONDUCTOR DEVICE HAVING THE SAME PATTERN

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of these items is that these references were discovered during any searches they or their client had made, or that they were considered in the preparation of the application.

Respectfully submitted,

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RJP/psf
April 21, 2004

PTO-1449





# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

Attorney Docket No.: **8020-1036**

Application No.: **10/774,463**

Applicant: **SAITO et al.**

Filing Date: **February 10, 2004**

Group Art Unit:

## U.S. PATENT DOCUMENTS

| Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing date (if appropriate) |
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## FOREIGN PATENT DOCUMENTS

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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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|---|---|---|
| | | Kawasaki et al., "AN ELECTROMIGRATION FAILURE MODEL OF TUNGSTEN PLUG CONTACTS / VIAS FOR REALISTIC LIFETIME PREDICTION", Symposium on VLSI Technology Digest of Technical Papers, pp. 192-193, 1996 |
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| EXAMINER: | DATE CONSIDERED |
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* Abstract provided for the Examiner's convenience